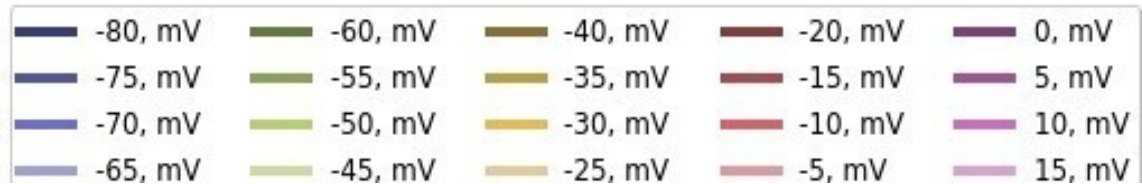
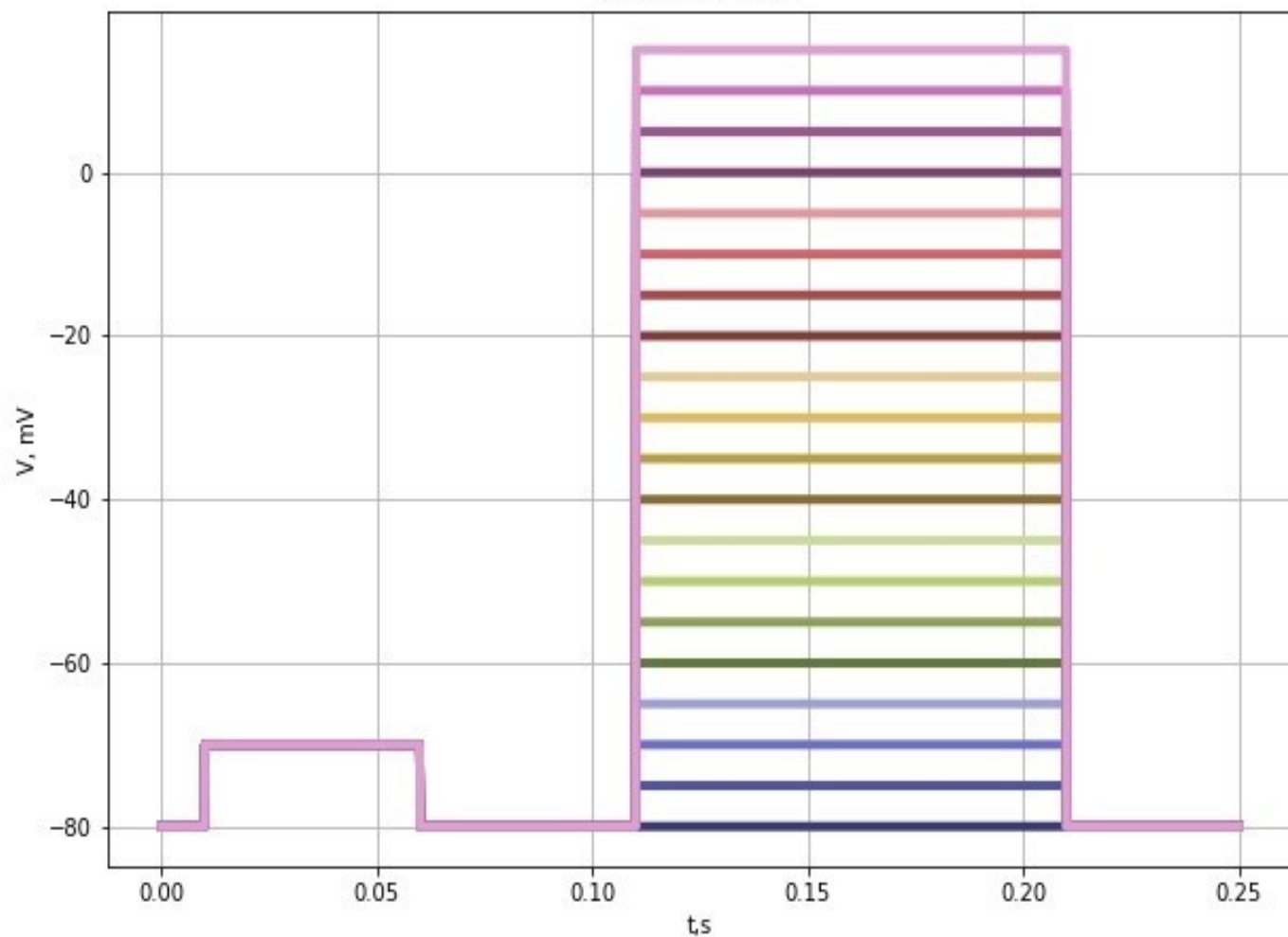
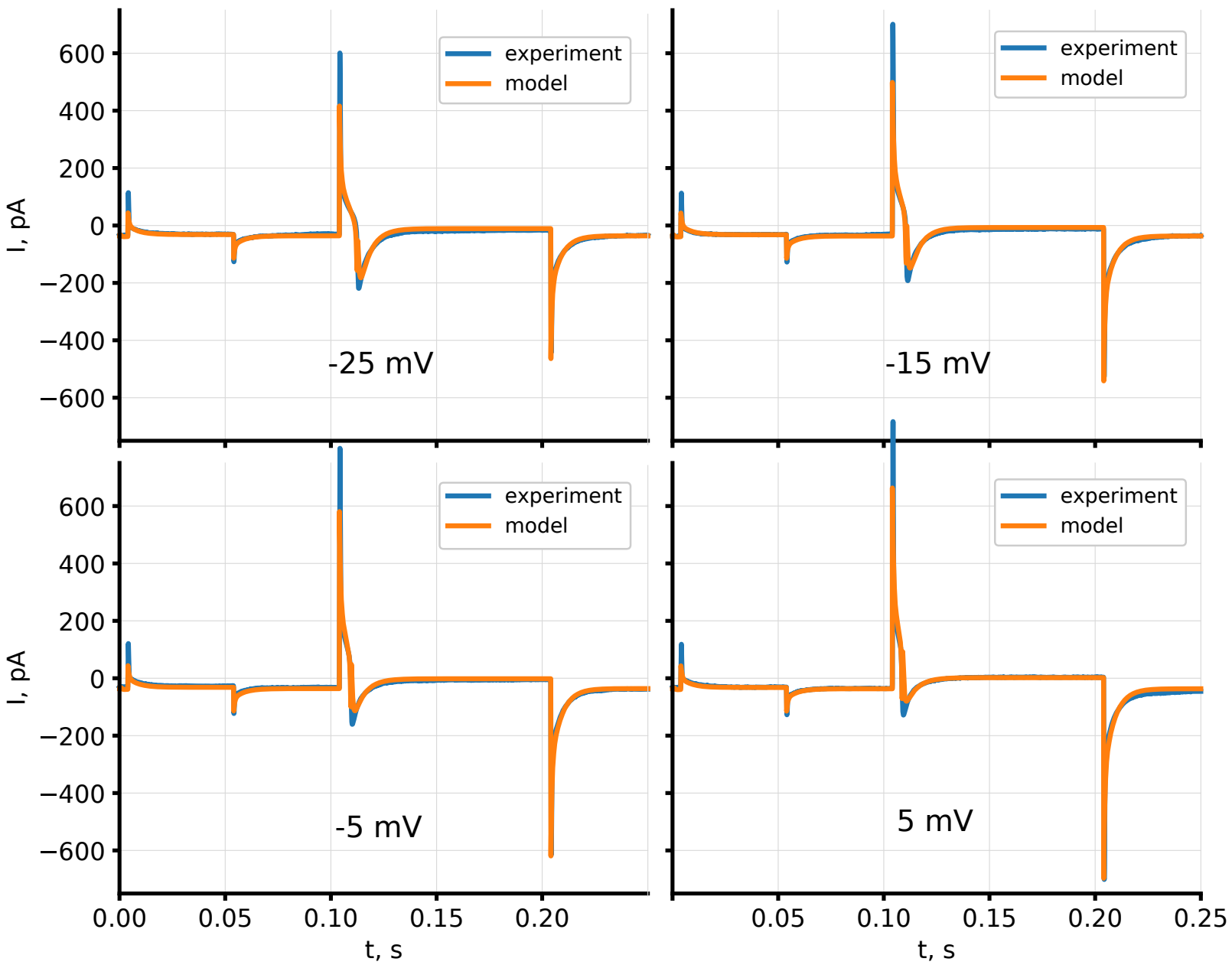
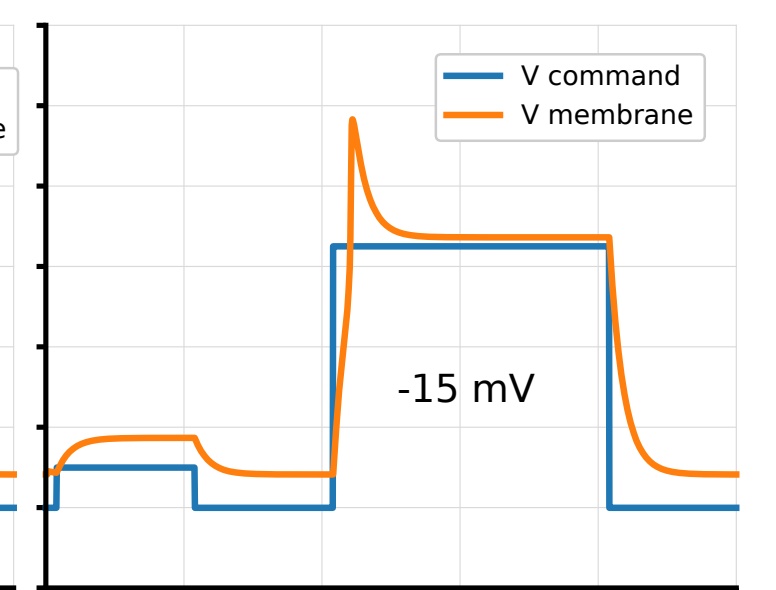
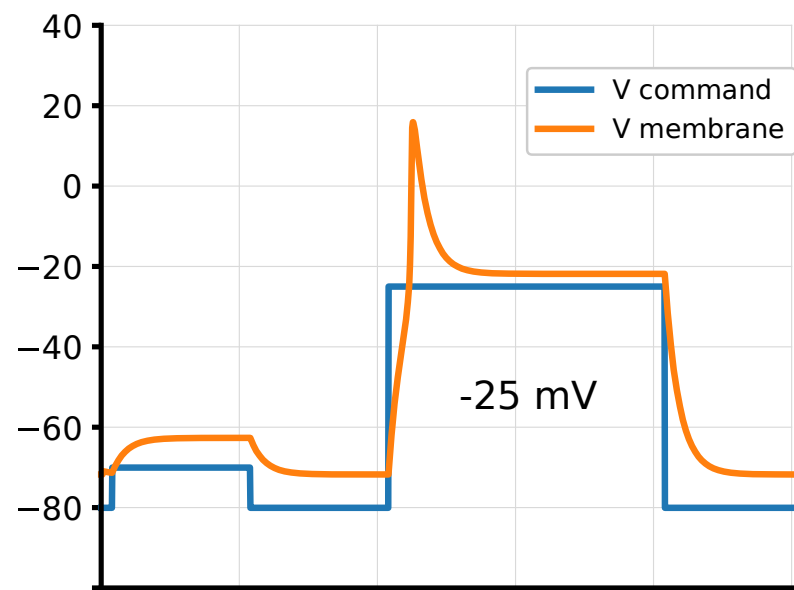


Protocol IV INa

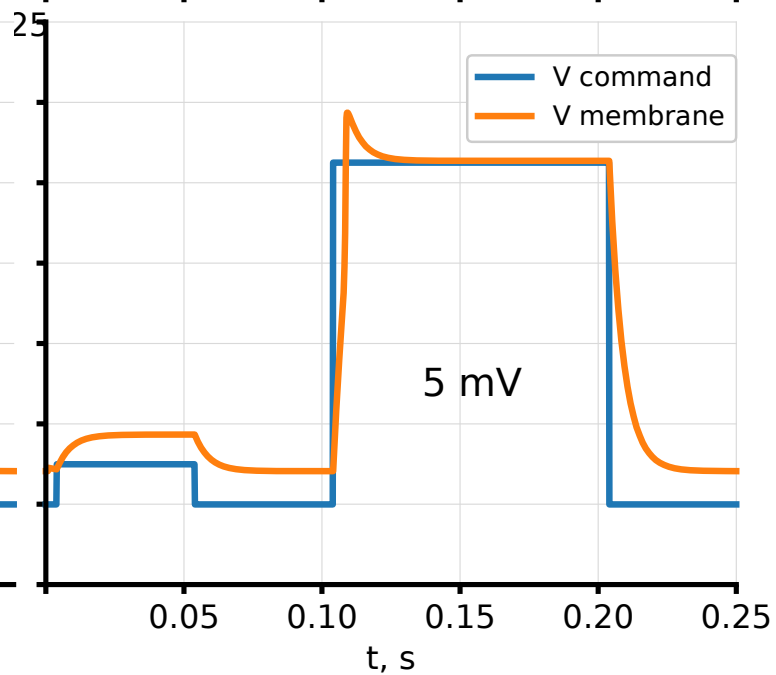
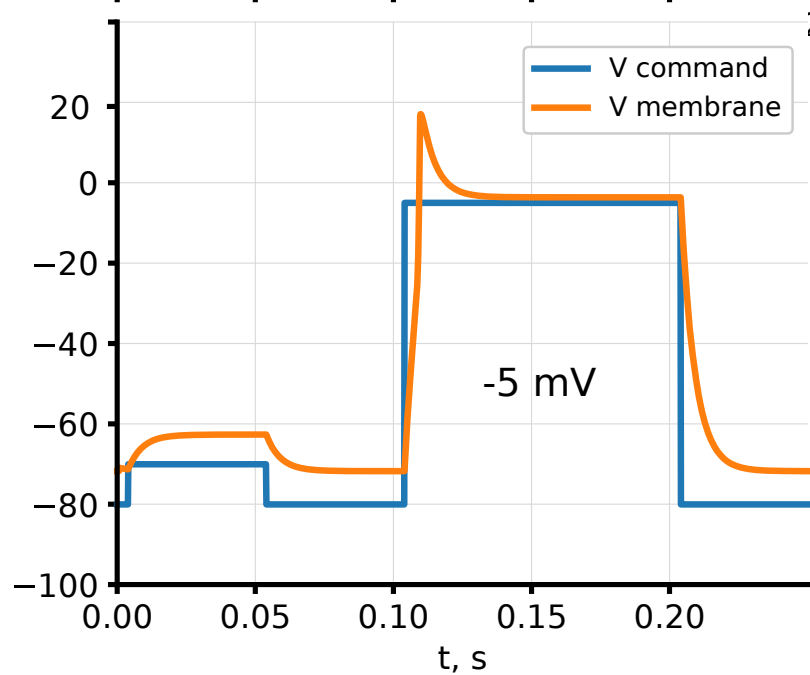


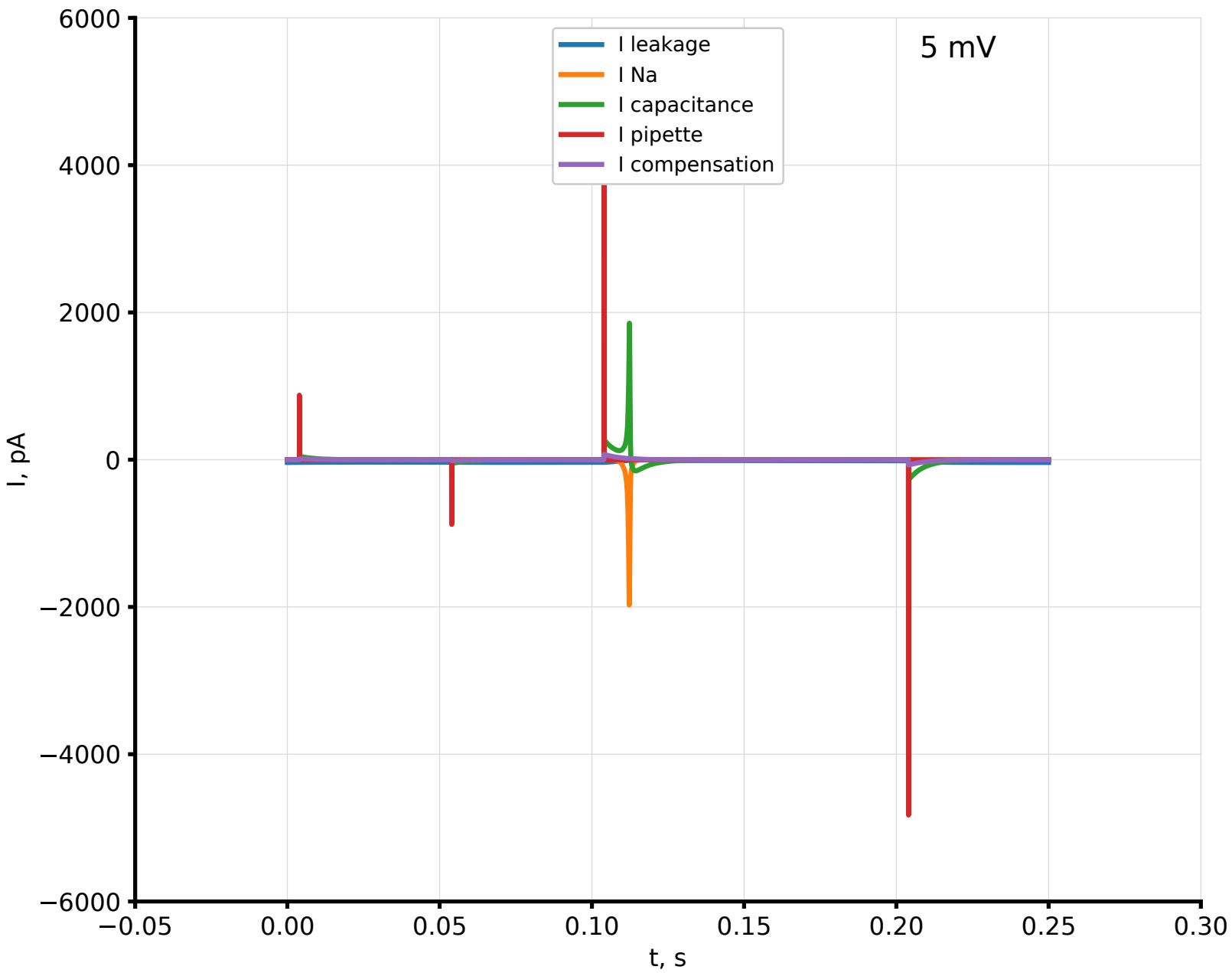


V, mV

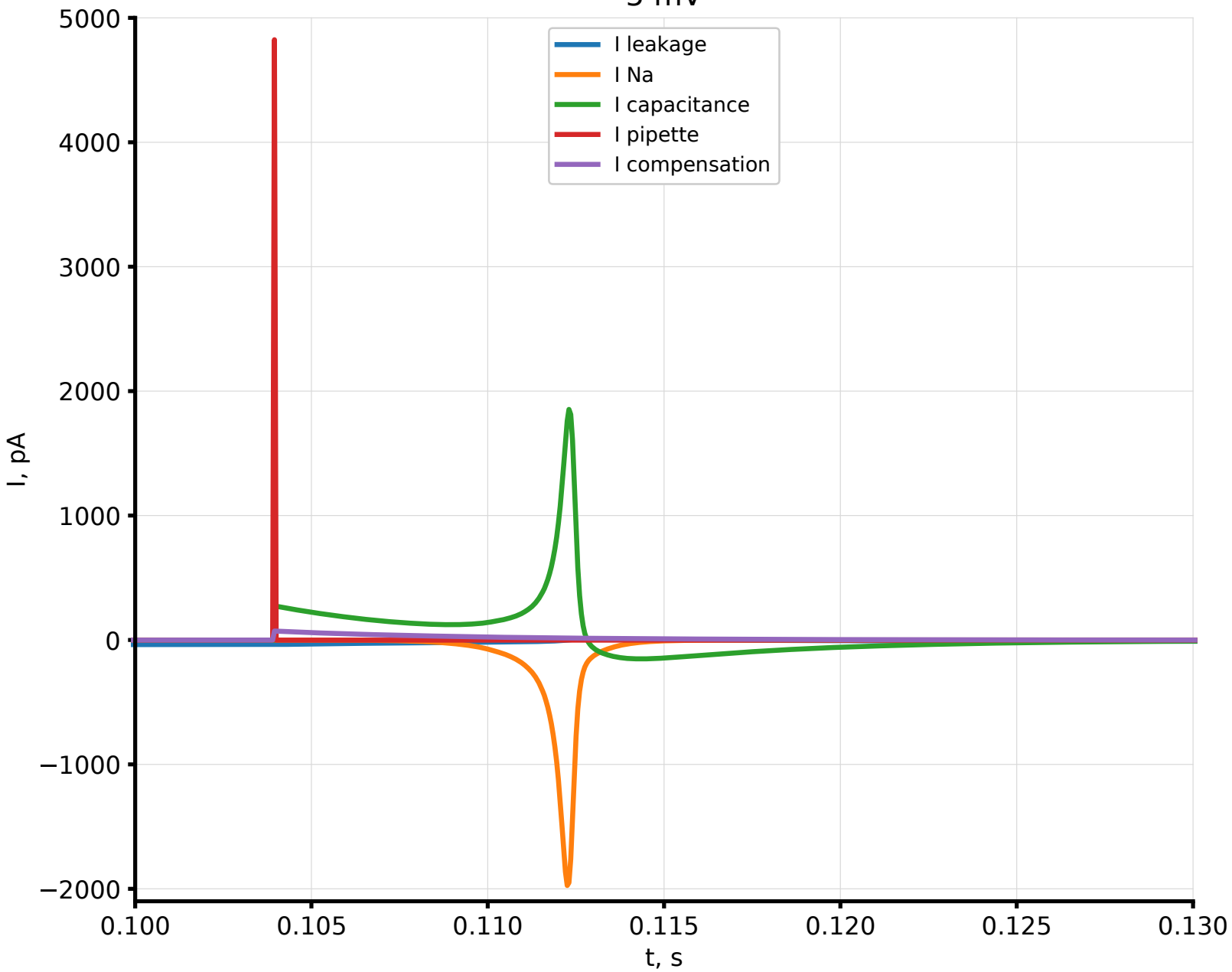


V, mV

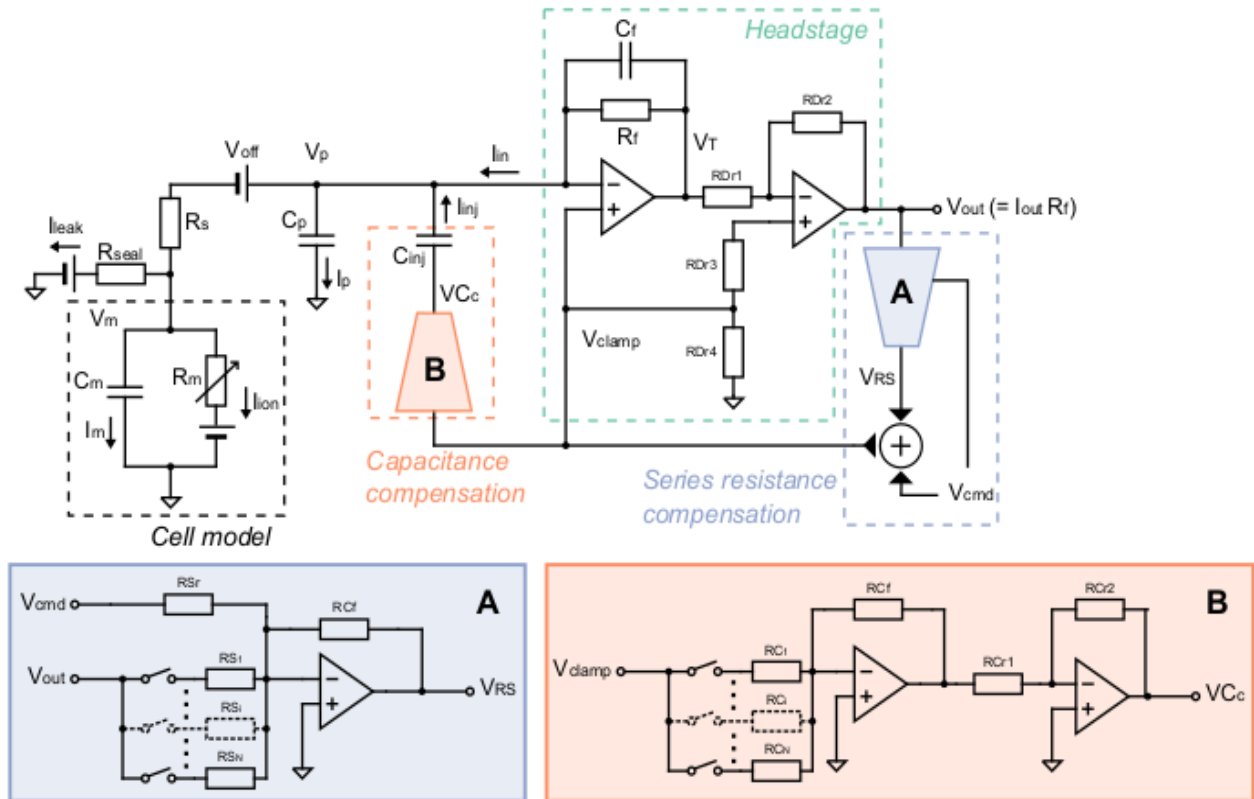




5 mV



Cxema patch-clamp



Lei Chon Lok, Clerx Michael, Whittaker Dominic G., Gavaghan David J., de Boer Teun P. and Mirams Gary R.

2020Accounting for variability in ion current recordings using a mathematical model of artefacts in voltage-clamp experimentsPhil. Trans. R. Soc. A.3782019034820190348
<http://doi.org/10.1098/rsta.2019.0348>

Параметры и расчет воротных переменных

$$\alpha_m = a_{0_m} * \exp^{\frac{v_m}{s_m}}$$

$$\beta_m = b_{0_m} * \exp^{\frac{v_m}{-\delta_m}}$$

$$\alpha_h = a_{0_h} * \exp^{\frac{v_m}{s_h}}$$

$$\beta_h = b_{0_h} * \exp^{\frac{v_m}{-\delta_h}}$$

$$\alpha_j = a_{0_j} * \exp^{\frac{v_m}{s_j}}$$

$$\beta_j = b_{0_j} * \exp^{\frac{v_m}{-\delta_j}}$$

$$\tau_m = \frac{1}{\beta_m + \alpha_m}$$

$$\tau_h = \frac{1}{\beta_h + \alpha_h}$$

$$\tau_j = \tau_{j_{const}} + \frac{1}{\beta_j + \alpha_j}$$

$$\frac{\partial m}{\partial t} = \frac{m_{inf} - m}{\tau_m}$$

$$\frac{\partial h}{\partial t} = \frac{h_{inf} - h}{\tau_h}$$

$$m_{inf} = \frac{1}{1 + \exp^{\frac{-V_{half_m} - V_m}{k_m}}}$$

$$h_{inf} = j_{inf} = \frac{1}{1 + \exp^{\frac{-V_{half_h} - V_m}{k_h}}}$$

Расчет потенциалов и ионных токов

$$\alpha = 0.75$$

$$\tau_{srp} = r_m * c_m * (1 - \alpha)$$

$$\beta = \frac{1}{1 - \alpha} - 1$$

$$\frac{\partial V_{comp}}{\partial t} = \frac{V_c - V_{comp}}{\tau_{srp}}$$

$$V_{cp} = V_c + (V_c - V_{comp}) * \beta$$

$$\frac{\partial V_p}{\partial t} = \frac{V_{cp} - V_p}{C_p * R_p}$$

$$\frac{\partial V_m}{\partial t} = \frac{V_p + V_{off} - V_m}{C_m * R_s} - \frac{I_{ion} + I_{leak}}{C_m}$$

$$I_m = C_m * \frac{\partial V_m}{\partial t}$$

$$I_p = C_p * \frac{\partial V_p}{\partial t}$$

$$I_p = x_{c_{comp}} * C_m * \frac{\partial V_{comp}}{\partial t}$$

$$I_{leak} = g_{leak} * V_m$$

$$I_{ion} = g_{ion} * m^3 * h * j * (V_m - V_{rev})$$

